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Bib Data Sheet

CONFIRMATION NO. 2890

SERIAL NUMBER 09/805,811	FILING DATE 03/13/2001 RULE	CLASS 324	GROUP ART UNIT 2862	ATTORNEY DOCKET NO. A-392	
APPLICANTS Saburo Uehara, Tokyo, JAPAN;					
** CONTINUING DATA *****					
** FOREIGN APPLICATIONS ***** JAPAN 2000-113071 04/14/2000					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 04/23/2001					
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Verified and <i>Manjitharan</i> Acknowledged Examiner's Signature Initials		STATE OR COUNTRY JAPAN	SHEETS DRAWING 5	TOTAL CLAIMS 5	INDEPENDENT CLAIMS 2
ADDRESS 802					
TITLE Semiconductor device testing apparatus and test method therefor					
FILING FEE RECEIVED 840	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT. No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		